


<b>Search Notes</b>  	<b>Application/Control No.</b>  10560154	<b>Applicant(s)/Patent Under Reexamination</b>  KAWAMURA ET AL.
	<b>Examiner</b>  Maikhanh Nguyen	<b>Art Unit</b>  2176

SEARCHED			
Class	Subclass	Date	Examiner
715	200, 201, 203, 205, 234, 700, 713, 716, 719, 721, 723, 728, 730, 760, 764, 850, 853, 854, FOR.206, FOR.207	4/24/09	MK
386	1, 4, 7, 8, 15, 16, 67, 107	4/24/09	MK
707	1,100,200,203,3,E17.001,E17.002,E17.013,E17.0	4/24/09	MK
UPDATED	ABOVE	11/8/09	MK

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Name Search	4/24/09	MK
West Search (USPAT, USPGPub, EPO, JPO, DWPI, TDBD) - See Search History	4/24/09	MK
West Updated - See Search History	11/8/09	MK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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